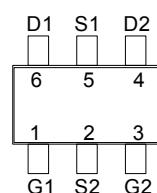
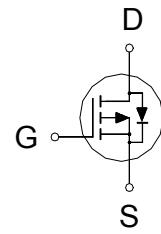
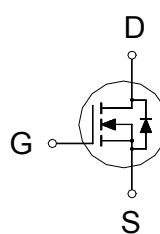


**NIKO-SEM****N- & P-Channel Enhancement Mode  
Field Effect Transistor****P5803NAG**  
TSOP-6  
Halogen-Free & Lead-Free**PRODUCT SUMMARY**

	$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
N-Channel	30V	58m $\Omega$	3A
P-Channel	-30V	115m $\Omega$	-2A



G : GATE  
D : DRAIN  
S : SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	N-Channel	P-Channel	UNITS
Drain-Source Voltage	$V_{DS}$	30	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V
Continuous Drain Current	$I_D$	3	-2	A
		2.3	-1.6	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	30	-10	
Power Dissipation	$P_D$	0.8	0.8	W
		0.5	0.5	
Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150		°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	Device	TYPICAL	MAXIMUM	UNITS
Junction-to- Ambient	$R_{\theta JA}$	N-Ch		160	°C / W
				160	

<sup>1</sup>Pulse width limited by maximum junction temperature.

**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	N-Ch	30		
		$V_{GS} = 0V, I_D = -250\mu\text{A}$	P-Ch	-30		
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	N-Ch	1	1.2	2.5
		$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	P-Ch	-1	-1.6	-2.5
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$	N-Ch			$\pm 100$
		$V_{DS} = 0V, V_{GS} = \pm 20V$	P-Ch			$\pm 100$

**NIKO-SEM**
**N- & P-Channel Enhancement Mode  
Field Effect Transistor**
**P5803NAG**  
**TSOP-6**  
**Halogen-Free & Lead-Free**

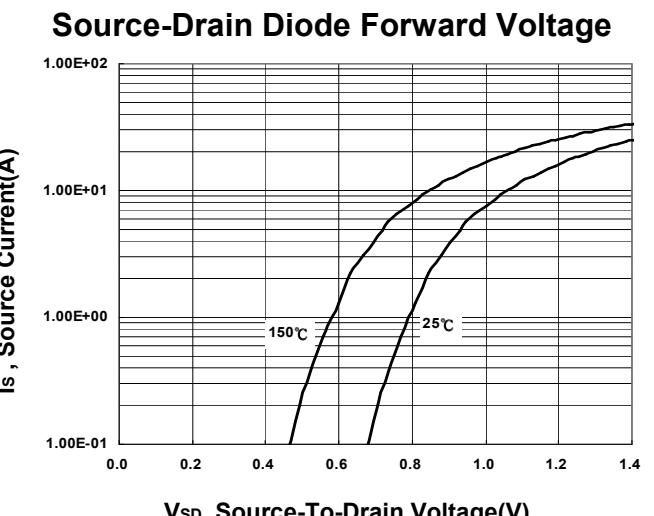
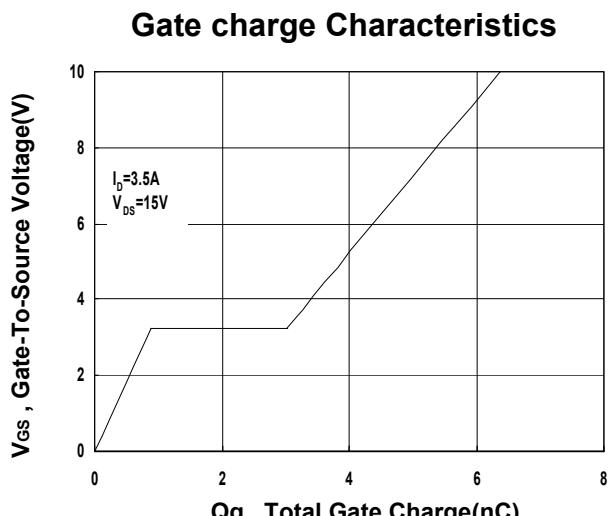
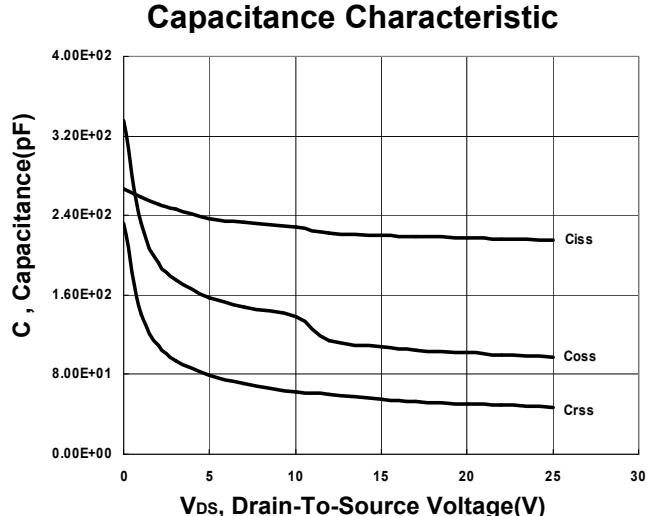
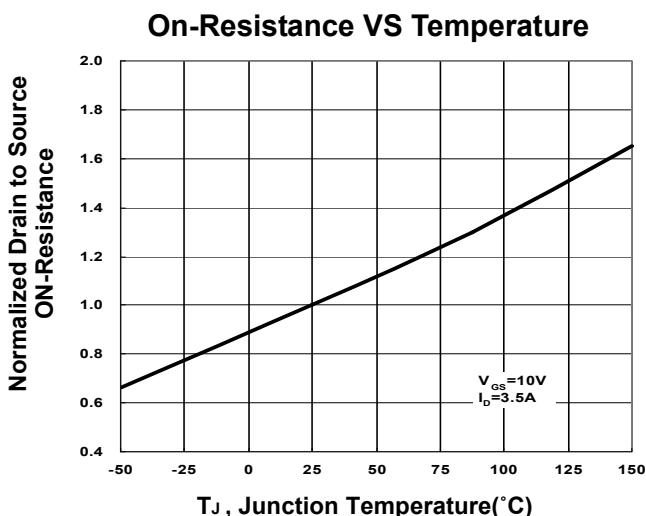
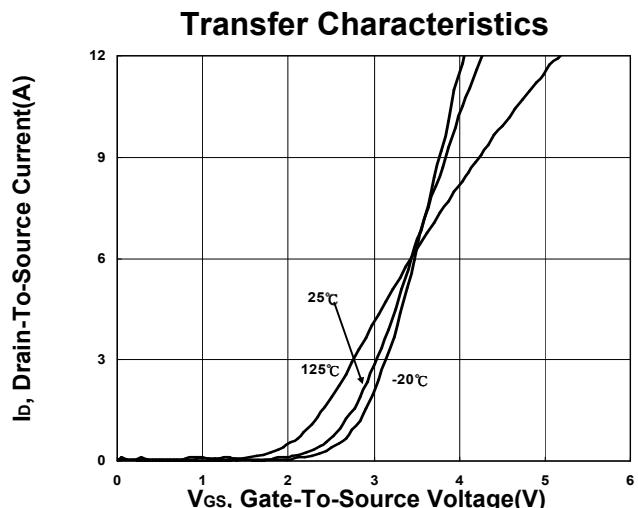
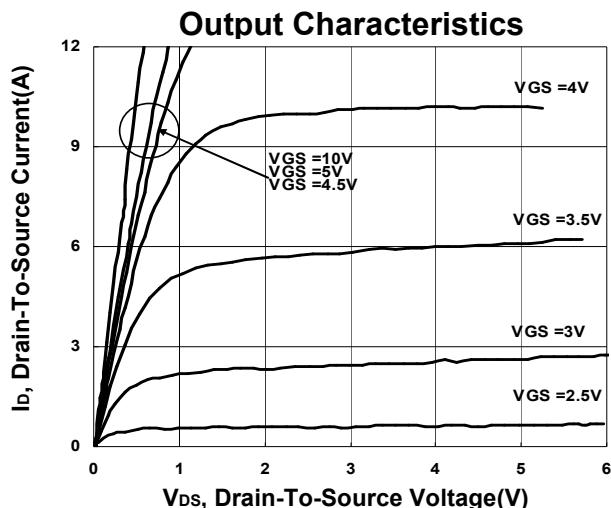
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 24V, V_{GS} = 0V$	N-Ch			1	$\mu A$
		$V_{DS} = -24V, V_{GS} = 0V$	P-Ch			-1	
		$V_{DS} = 20V, V_{GS} = 0V, T_J = 55^\circ C$	N-Ch			10	
			P-Ch			-10	
On-State Drain Current <sup>1</sup>	$I_{D(ON)}$	$V_{DS} = 5V, V_{GS} = 10V$	N-Ch	30			A
		$V_{DS} = -5V, V_{GS} = -10V$	P-Ch	-10			
Drain-Source On-State resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 2A$	N-Ch		68	88	$m\Omega$
		$V_{GS} = -4.5V, I_D = -1.5A$	P-Ch		157	185	
		$V_{GS} = 10V, I_D = 3.5A$	N-Ch		47	58	
		$V_{GS} = -10V, I_D = -2.3A$	P-Ch		96	115	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 5V, I_D = 3.5A$	N-Ch		6		S
		$V_{DS} = -5V, I_D = -2.3A$	P-Ch		4		

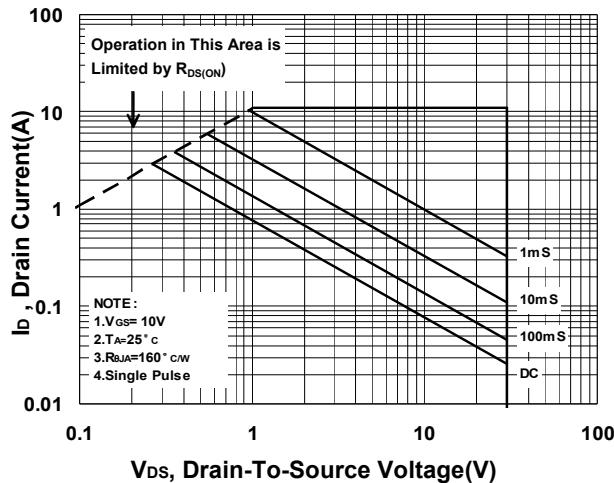
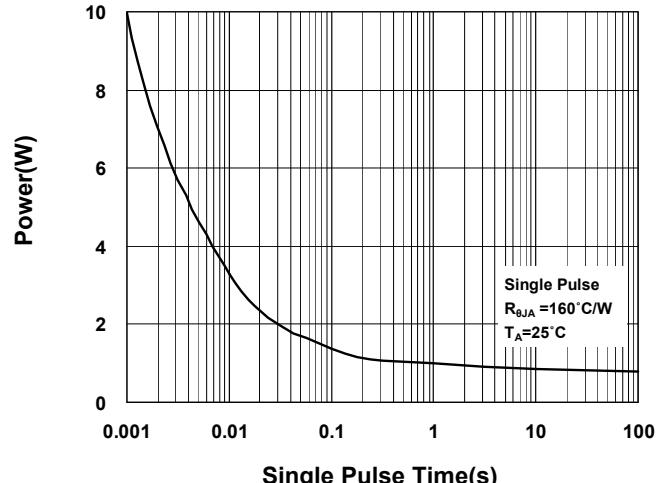
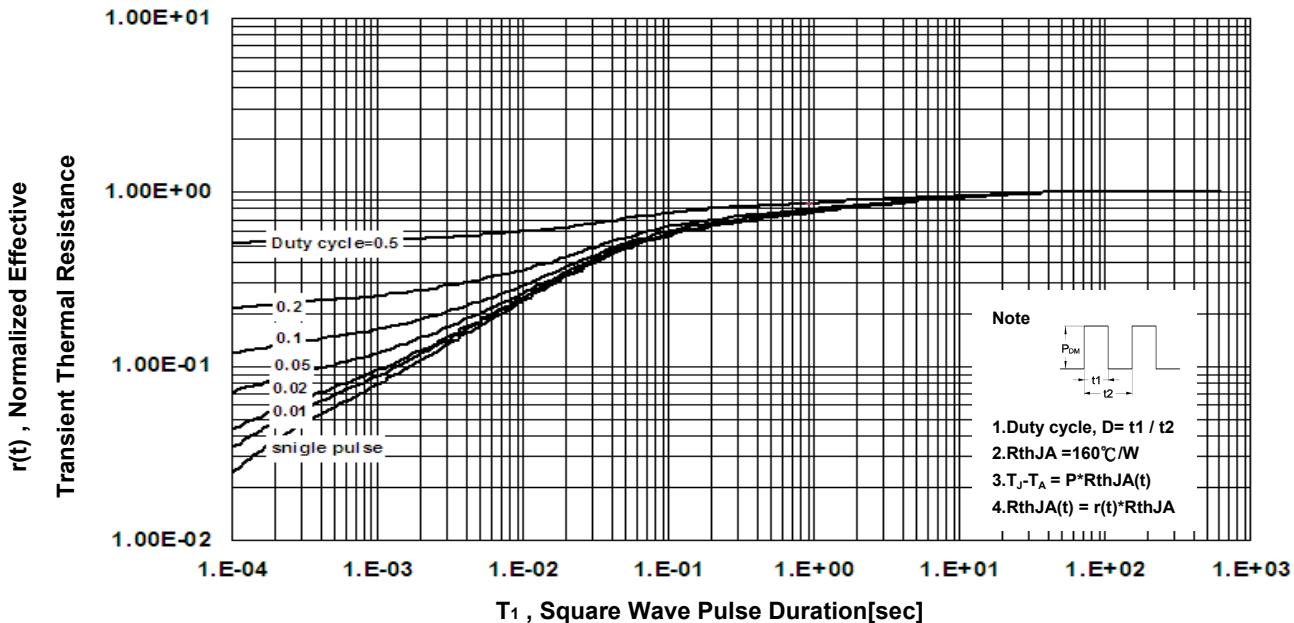
DYNAMIC							
Input Capacitance	$C_{iss}$	N-Channel $V_{GS} = 0V, V_{DS} = 15V,$ $f = 1MHz$ P-Channel $V_{GS} = 0V, V_{DS} = -15V,$ $f = 1MHz$	N-Ch		216		pF
Output Capacitance	$C_{oss}$		P-Ch		261		
Reverse Transfer Capacitance	$C_{rss}$		N-Ch		99		
Reverse Transfer Capacitance	$C_{rss}$		P-Ch		105		
Total Gate Charge <sup>2</sup>	$Q_g$	N-Channel $V_{DS} = 0.5V_{(BR)DSS}, V_{GS} = 10V$ $I_D = 3.5A$ P-Channel $V_{DS} = 0.5V_{(BR)DSS}, V_{GS} = 10V$ $I_D = -2.3A$	N-Ch		47		nC
Gate-Source Charge <sup>2</sup>	$Q_{gs}$		P-Ch		48		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$		N-Ch		6.5		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$		P-Ch		6.5		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	N-Channel $V_{DS} = 15V$ $I_D \cong 3.5A, V_{GS} = 10V, R_{GEN} = 6\Omega$ P-Channel $V_{DS} = -15V,$ $I_D \cong -2.3A, V_{GS} = -10V, R_{GEN} = 6\Omega$	N-Ch		1		nS
Rise Time <sup>2</sup>	$t_r$		P-Ch		1.1		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$		N-Ch		2.3		
Fall Time <sup>2</sup>	$t_f$		P-Ch		2.1		

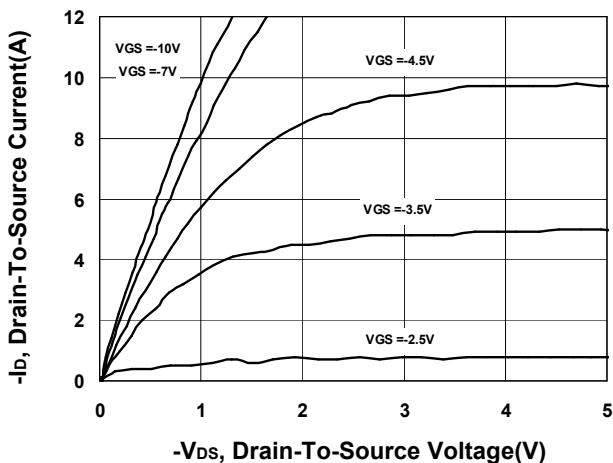
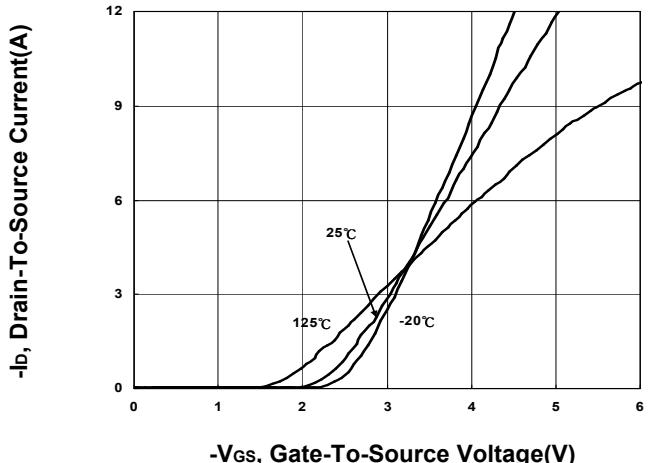
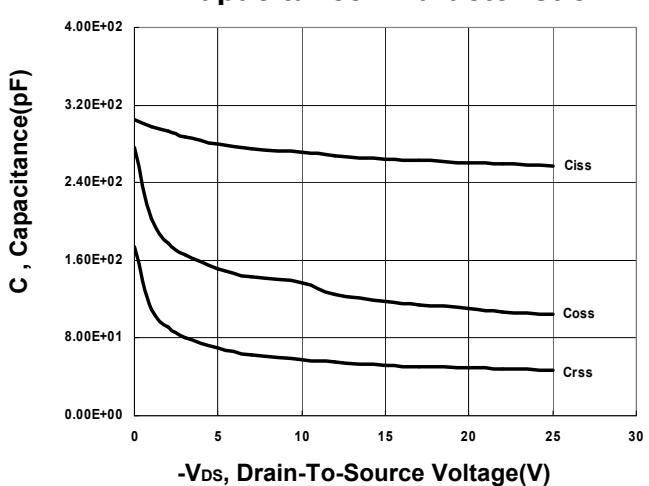
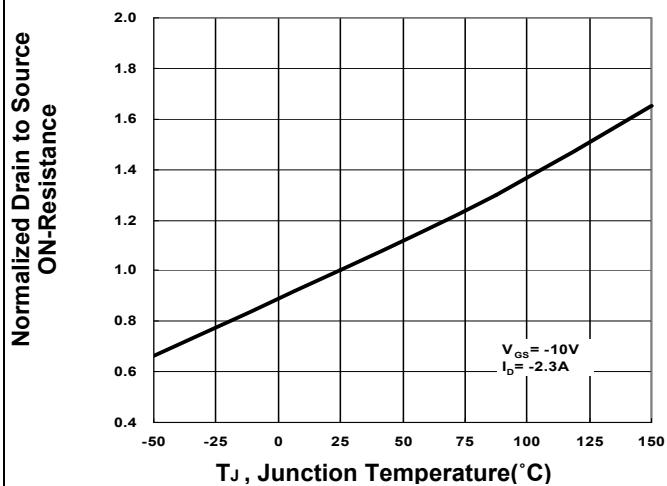
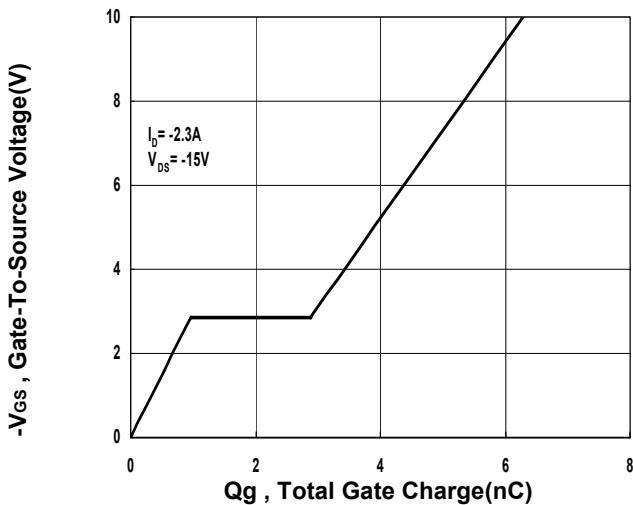
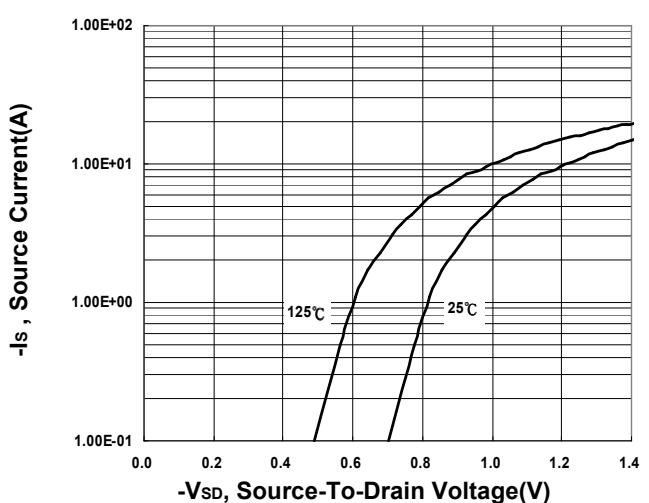
**NIKO-SEM****N- & P-Channel Enhancement Mode  
Field Effect Transistor****P5803NAG  
TSOP-6  
Halogen-Free & Lead-Free****SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T<sub>J</sub> = 25 °C)**

Continuous Current	I <sub>S</sub>		N-Ch			3 -2	A
Forward Voltage <sup>1</sup>	V <sub>SD</sub>	I <sub>F</sub> = 2.3A, V <sub>GS</sub> = 0V	N-Ch			1.3	V
		I <sub>F</sub> = -2.1A, V <sub>GS</sub> = 0V	P-Ch			-1.3	
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 3.5A, dI <sub>F</sub> /dt = 100A / μS	N-Ch		12.7		nS
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = -2.3A, dI <sub>F</sub> /dt = 100A / μS	P-Ch		12.4	6	nC
						5	

<sup>1</sup>Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.<sup>2</sup>Independent of operating temperature.

**NIKO-SEM****N- & P-Channel Enhancement Mode  
Field Effect Transistor****P5803NAG  
TSOP-6  
Halogen-Free & Lead-Free****TYPICAL PERFORMANCE CHARACTERISTICS  
N-CHANNEL**

**Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**

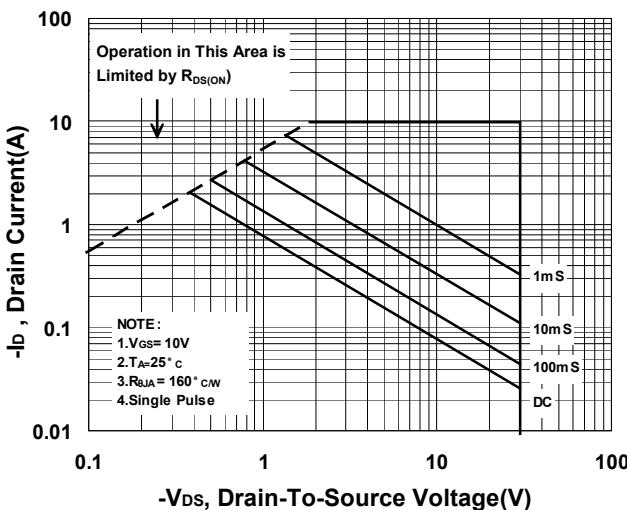
**NIKO-SEM****N- & P-Channel Enhancement Mode  
Field Effect Transistor****P5803NAG  
TSOP-6  
Halogen-Free & Lead-Free****TYPICAL PERFORMANCE CHARACTERISTICS  
P-CHANNEL****Output Characteristics****Transfer Characteristics****On-Resistance VS Temperature****Gate charge Characteristics****Source-Drain Diode Forward Voltage**

**NIKO-SEM**

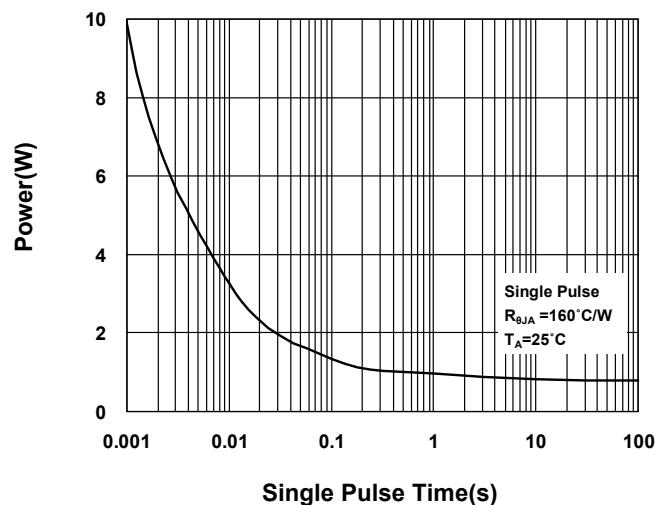
**N- & P-Channel Enhancement Mode  
Field Effect Transistor**

**P5803NAG**  
**TSOP-6**  
**Halogen-Free & Lead-Free**

### Safe Operating Area



### Single Pulse Maximum Power Dissipation



### Transient Thermal Response Curve

